

WEST Search History

DATE: Thursday, July 25, 2002

Set Name Query side by side

Hit Count Set Name result set

DB=USPT,PGPB; PLUR=YES; OP=ADJ

L12	L9 and (chloric adj acid) and (sulfuric adj acid)	6	L12
L11	L9 and pd<19990716	6	L11
L10	L9 and pd<20000713	6	L10
L9	L5 and (hydrogen near2 peroxide)	6	L9
L8	L7 and pd<20000713	34	L8
L7	L3 and (hydrogen near2 peroxide)	34	L7

DB=USPT,PGPB,JPAB,EPAB,DWPI,TDBD; PLUR=YES; OP=ADJ

L6	L5 and @pd<20000713	5	L6
L5	L4 and (silicon adj \$3oxide)	15	L5
L4	L3 and semiconductor	19	L4
L3	clean\$5 and oxid\$3 and sulfate and (chloric adj acid)	91	L3
L2	clean\$5 and oxid\$3 and (hydro adj sulfate) and (chloric adj acid)	0	L2
L1	clean\$5 and oxid\$3 and (hydro adj sulfate) and (chloric adj acid) and H2O2	0	L1

END OF SEARCH HISTORY

	U	1	Document ID	Issue Date	Pages
1	<input type="checkbox"/>	<input type="checkbox"/>	US 20020012123 A1	20020131	9
2	<input type="checkbox"/>	<input checked="" type="checkbox"/>	US 6331890 B1	20011218	27
3	<input type="checkbox"/>	<input type="checkbox"/>	US 5955377 A	19990921	70
4	<input type="checkbox"/>	<input type="checkbox"/>	US 5631171 A	19970520	71

	U	1	Document ID	Issue Date	Pages
5	<input type="checkbox"/>	<input type="checkbox"/>	US 5541057 A	19960730	71
6	<input type="checkbox"/>	<input type="checkbox"/>	US 5494829 A	19960227	69

	U	1	Document ID	Issue Date	Pages
-	<input type="checkbox"/>	<input type="checkbox"/>	US 5482830 A	19960109	72
8	<input type="checkbox"/>	<input type="checkbox"/>	US 5468606 A	19951121	63
9	<input type="checkbox"/>	<input checked="" type="checkbox"/>	US 4606641 A	19860819	12

	U	1	Document ID	Issue Date	Pages
10	<input type="checkbox"/>	<input type="checkbox"/>	US 4521522 A	19850604	8

	Title	Current OR	Current XRef
1	Spatial averaging technique for ellipsometry and reflectometry	356/369	438/14
2	Thickness measuring apparatus, substrate processing method, and substrate processing apparatus	356/369	356/364; 356/630; 414/255
3	Methods and kits for the amplification of thin film based assays	436/518	356/364; 356/369; 356/370; 422/55; 422/57; 422/82.05; 422/82.11; 435/283.1; 435/287.2; 435/287.9; 435/288.7; 435/5; 435/7.21; 435/7.32; 435/7.9; 435/7.92; 435/7.94; 435/808; 435/810; 436/164; 436/524; 436/525; 436/527; 436/531; 436/532; 436/533; 436/805
4	Method and instrument for detection of change of thickness or refractive index for a thin film substrate	436/518	356/364; 356/369; 422/55; 422/82.05; 435/5; 435/808; 436/164; 436/524; 436/525; 436/527; 436/805

	Title	Current OR	Current XRef
5	Methods for detection of an analyte	435/5	356/369; 359/540; 359/581; 359/535; 422/55; 422/57; 422/58; 435/287.2; 435/6; 435/7.21; 435/7.22; 435/7.23; 435/7.32; 435/7.34; 435/808; 436/164; 436/513; 436/524; 436/525; 436/527; 436/531; 436/805
6	Devices and methods for detection of an analyte based upon light interference	436/518	356/364; 356/369; 422/55; 422/82.05; 435/808; 436/164; 436/524; 436/525; 436/527; 436/805

	Title	Current OR	Current XRef
7	Devices and methods for detection of an analyte based upon light interference	435/5	356/369; 359/580; 359/585; 359/586; 359/589; 422/55; 422/57; 422/58; 422/82.05; 435/7.21; 435/7.22; 435/7.32; 435/7.36; 435/808; 436/164; 436/510; 436/513; 436/518; 436/524; 436/525; 436/527; 436/805
8	Devices for detection of an analyte based upon light interference	435/5	356/369; 359/580; 359/581; 359/585; 359/586; 422/55; 422/57; 422/58; 422/82.05; 435/287.2; 435/6; 435/7.21; 435/7.22; 435/7.23; 435/7.32; 435/7.34; 435/808; 436/164; 436/513; 436/524; 436/525; 436/527; 436/531; 436/805
9	Apparatus for measuring film thickness	356/369	356/632

	Title	Current OR	Current XRef
10	Optical specific binding assay with reflection of polarized electromagnetic radiation	436/525	356/364; 436/164; 436/500; 436/527; 436/531; 436/805

	Retrieval Classif	Inventor	S	C	P	2	3	4	5
1		Wei, Lanhua et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
2		Marumo, Yoshinori et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
3		Maul, Diana M. et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
4		Sandstrom, Torbjorn et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>

	Retrieval Classif	Inventor	S	C	P	2	3	4	5
5		Bogart, Gregory R. et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
6		Sandstrom, Torbjorn et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>

	Retrieval Classif	Inventor	S	C	P	2	3	4	5
7		Bogart, Gregory R. et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
8		Bogart, Gregory R. et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>
9		Yamada, Takeo et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>

	Retrieval Classif	Inventor	S	C	P	2	3	4	5
10		Lundstrom, Kurt I. et al.	<input checked="" type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>	<input type="checkbox"/>

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1	US 20020012123	<input type="checkbox"/>
2	US 6331890	<input type="checkbox"/>
3	US 5955377	<input type="checkbox"/>
4	US 5631171	<input type="checkbox"/>

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5	US 5541057	<input type="checkbox"/>
6	US 5494829	<input type="checkbox"/>

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7	US 5482830	<input type="checkbox"/>
8	US 5468606	<input type="checkbox"/>
9	US 4606641	<input type="checkbox"/>

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10	US 4521522	<input type="checkbox"/>

	Type	L #	Hits	Search Text	DBs	Time Stamp
1	IS&F	L1	592	(356/381,364,366,367,370,908).CCLS.	USPAT; US-PGP UB	2002/07/25 14:58
2	IS&F	L2	0	("L1 and (silicon adj \$3oxide) and thickness and polarimet\$4").PN.	USPAT; US-PGP UB	2002/07/25 15:00
3	IS&F	L3	0	("L1 and (silicon adj \$3oxide) and thickness and ellipsomet\$7").PN.	USPAT; US-PGP UB	2002/07/25 15:00
4	IS&R	L4	0	("oxide and measur\$7 and thickness and ellipsomet\$7").PN.	USPAT; US-PGP UB; EPO; JPO; DERWEN T; IBM_TD E	2002/07/25 15:01
5	BFS	L5	13	L1 and (silicon adj \$3oxide) and thickness and ellipsomet\$4	USPAT; US-PGP UB	2002/07/25 15:03
6	BFS	L6	10	L5 and @pd<20000713	USPAT; US-PGP UB	2002/07/25 15:10
7	BFS	L7	0	L1 and (oxid\$4 near3 growth)	USPAT; US-PGP UB	2002/07/25 15:11
8	BFS	L8	10	oxid\$4 near3 growth near2 monitor\$5	USPAT; US-PGP UB	2002/07/25 15:12
9	BFS	L9	2	L8 and silicon adj dioxide	USPAT; US-PGP UB	2002/07/25 15:18

	Comments	Error Definition	Errors
1			0
2			0
3			0
4			0
5			0
6			0
7			0
8			0
9			0

	Type	L #	Hits	Search Text	DBs	Time Stamp
10	BFS	L10	1114	oxide near3 film and thickness near3 variation	USPAT; US-PGP UB; EPO; JPO; DEFWEN T; IBM_TD E	2002/07/25 15:24
11	BFS	L11	1	L1 and L10	USPAT; US-PGP UB; EPO; JPO; DEFWEN T; IBM_TD E	2002/07/25 15:21
12	IS&R	L12	1143	(356/381, 908, 364-370).CCLS.	USPAT; US-PGP UB	2002/07/25 15:22
13	BFS	L13	2	L10 and L12	USPAT; US-PGP UB	2002/07/25 15:23
14	BFS	L14	253	L10 and (contaminat\$4 or dirt\$5)	USPAT; US-PGP UB; EPO; JPO; DEFWEN T; IBM_TD E	2002/07/25 15:25
15	BFS	L15	1	L14 and (thickness near3 correction)	USPAT; US-PGP UB; EPO; JPO; DEFWEN T; IBM_TD E	2002/07/25 16:06

	Comments	Error Definition	Errors
10			0
11			0
12			0
13			0
14			0
15			0

	Type	L #	Hits	Search Text	DBs	Time Stamp
16	BRS	L16	25	L12 and oxide near4 thickness near4 measur\$7	USPAT; US-PGP UB; EPO; JPO; 2002/07/25 DERWEN: 16:16 T; IBM_TD B	
17	BFS	L17	0	L16 and "ln(t)"	USPAT; US-PGP UB; EPO; JPO; 2002/07/25 DERWEN: 16:09 T; IBM_TD B	
18	BFS	L18	190702 1	L16 and ln(t)	USPAT; US-PGP UB; EPO; JPO; 2002/07/25 DERWEN: 16:16 T; IBM_TD B	
19	BFS	L19	0	L1 and "ln(t)"	USPAT; US-PGP UB; EPO; JPO; 2002/07/25 DERWEN: 16:16 T; IBM_TD B	
20	BRS	L20	190702 1	L13 and ln(t)	USPAT; US-PGP UB; EPO; JPO; 2002/07/25 DERWEN: 16:16 T; IBM_TD B	

	Comments	Error Definition	Errors
16			0
17			0
18			0
19			0
20			0

	Type	L #	Hits	Search Text	DBs	Time Stamp
21	BFS	L21	38	L10 and oxide near4 thickness near4 measur\$7	USPAT; US-PGF UB; EPO; JPO; DEFWEN T; IBM_TD B	2002/07/25 16:17
22	BFS	L22	0	L21 and "ln(t)"	USPAT; US-PGF UB; EPO; JPO; DEFWEN T; IBM_TD B	2002/07/25 16:17
23	BFS	L23	10	L12 and (apparent near3 thickness)	USPAT; US-PGF UB; EPO; JPO; DEFWEN T; IBM_TD B	2002/07/25 16:36
24	BFS	L24	0	L23 and Fig. 17	USPAT; US-PGF UB; EPO; JPO; DEFWEN T; IBM_TD B	2002/07/25 16:37
25	BFS	L25	0	L23 and Fig.17	USPAT; US-PGF UB; EPO; JPO; DEFWEN T; IBM_TD B	2002/07/25 16:37

	Comments	Error Definition	Errors
21			0
22			0
23			0
24			0
25			0

	Type	L #	Hits	Search Text	DBs	Time Stamp
26	BFS	L26	1	L23 and FIG. 15	USPAT; US-PGP UB; EPO; JPO; 2002/07/25 DERWEN 16:37 T; IBM_TD B	
27	BFS	L27	0	L23 and FIG. 17	USPAT; US-PGP UB; EPO; JPO; 2002/07/25 DERWEN 16:37 T; IBM_TD B	
28	BFS	L29	1148	L23 and FIG. 12	USPAT; US-PGP UB; EPO; JPO; 2002/07/25 DERWEN 16:37 T; IBM_TD B	
29	BFS	L28	2	L23 and FIG. 13	USPAT; US-PGP UB; EPO; JPO; 2002/07/25 DERWEN 16:38 T; IBM_TD B	

	Comments	Error Definition	Errors
26			0
27			0
28			0
29			0